

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

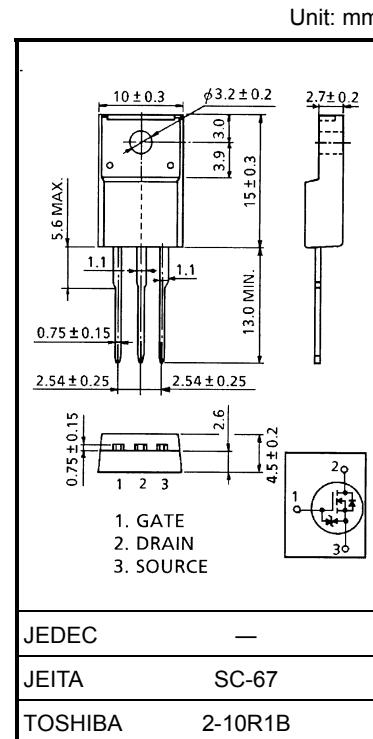
# 2SK3754

## Relay Drive, DC-DC Converter and Motor Drive Applications

- 4.5-V gate drive
- Low drain-source ON resistance:  $R_{DS(ON)} = 71 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 5.0 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = 10 \mu\text{A}$  (max) ( $V_{DS} = 30 \text{ V}$ )
- Enhancement-model:  $V_{th} = 1.8 \sim 2.5 \text{ V}$  ( $V_{DS} = 10 \text{ V}$ ,  $I_D = 1 \text{ mA}$ )

## Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Drain-source voltage	$V_{DSS}$	30	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	$V_{DGR}$	30	V
Gate-source voltage	$V_{GSS}$	$\pm 20$	V
Drain current	DC (Note 1)	$I_D$	A
	Pulse (Note 1)	$I_{DP}$	
Drain power dissipation ( $T_c = 25^\circ\text{C}$ )	$P_D$	25	W
Single pulse avalanche energy (Note 2)	$E_{AS}$	4.0	mJ
Avalanche current	$I_{AR}$	2.5	A
Repetitive avalanche energy (Note 3)	$E_{AR}$	2.5	mJ
Channel temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55~150	$^\circ\text{C}$



Weight: 1.9 g (typ.)

## Thermal Characteristics

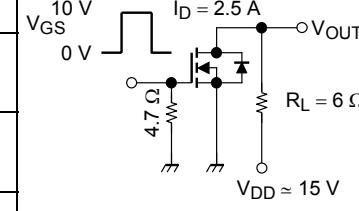
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th}(\text{ch-c})$	5.0	$^\circ\text{C/W}$
Thermal resistance, channel to ambient	$R_{th}(\text{ch-a})$	62.5	$^\circ\text{C/W}$

Note 1: Please use devices on conditions that the channel temperature is below  $150^\circ\text{C}$ .Note 2:  $V_{DD} = 24 \text{ V}$ ,  $T_{ch} = 25^\circ\text{C}$  (initial),  $L = 0.5 \text{ mH}$ ,  $R_G = 25 \Omega$ ,  $I_{AR} = 2.5 \text{ A}$ 

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

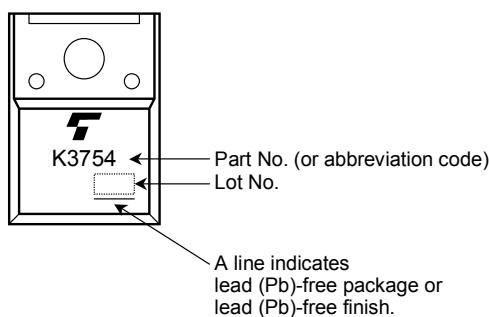
Electrical Characteristics ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	$I_{GSS}$	$V_{GS} = \pm 16\text{ V}$ , $V_{DS} = 0\text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Drain cut-off current	$I_{DSS}$	$V_{DS} = 30\text{ V}$ , $V_{GS} = 0\text{ V}$	—	—	10	$\mu\text{A}$
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	$I_D = 10\text{ mA}$ , $V_{GS} = 0\text{ V}$	30	—	—	V
	$V_{(\text{BR})\text{DSX}}$	$I_D = 10\text{ mA}$ , $V_{GS} = -20\text{ V}$	15	—	—	
Gate threshold voltage	$V_{th}$	$V_{DS} = 10\text{ V}$ , $I_D = 1\text{ mA}$	1.3	—	2.5	V
Drain-source ON resistance	$R_{DS\text{ (ON)}}$	$V_{GS} = 4.5\text{ V}$ , $I_D = 2.5\text{ A}$	—	78	99	$\text{m}\Omega$
		$V_{GS} = 10\text{ V}$ , $I_D = 2.5\text{ A}$	—	71	89	
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = 10\text{ V}$ , $I_D = 2.5\text{ A}$	2.5	5.0	—	S
Input capacitance	$C_{iss}$	$V_{DS} = 10\text{ V}$ , $V_{GS} = 0\text{ V}$ , $f = 1\text{ MHz}$	—	1250	—	pF
Reverse transfer capacitance	$C_{rss}$		—	155	—	
Output capacitance	$C_{oss}$		—	170	—	
Switching time	Rise time	$t_r$	 $V_{GS}$ (0 V to 10 V)	—	7	ns
	Turn-on time	$t_{on}$		—	16	
	Fall time	$t_f$		—	18	
	Turn-off time	$t_{off}$		—	69	
Total gate charge	$Q_g$	$V_{DD} \approx 24\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 5\text{ A}$	—	25	—	nC
Gate-source charge	$Q_{gs}$		—	20	—	
Gate-drain charge	$Q_{gd}$		—	5	—	

Source-Drain Ratings and Characteristics ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	—	—	—	5	A
Pulse drain reverse current (Note 1)	$I_{DRP}$	—	—	—	15	A
Reverse recovery time	$t_{rr}$	$I_{DR} = 5\text{ A}$ , $V_{GS} = 0\text{ V}$ , $dI_{DR}/dt = 50\text{ A}/\mu\text{s}$	—	37	—	ns
Reverse recovery charge	$Q_{rr}$		—	20	—	nC

## Marking



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